

AOUS66616

60V N-Channel AlphaSGT™

General Description

- Trench Power MOSFET AlphaSGT[™] technology
- Low R_{DS(ON)}
- Excellent Gate Charge x R_{DS(ON)} Product (FOM)
- RoHS and Halogen-Free Compliant

Product Summary

 $\rm V_{\rm DS}$ 60V I_D (at $V_{GS}=10V$) 92A R_{DS(ON)} (at V_{GS}=10V) < 3.3mΩ R_{DS(ON)} (at V_{GS}=6V) < 4.7mΩ

100% UIS Tested 100% Rg Tested

Form

35

184

92.5

37

6.2

4.0



Applications

• Synchronous Rectification in DC/DC and AC/DC Converters

L=0.3mH

T_C=25°C

T_C=100°C

T_A=25°C

T_A=70°C

• Industrial and Motor Drive applications

Orderable Part Number

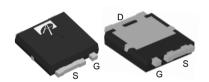
Avalanche Current C

Power Dissipation ^B

Power Dissipation ^A

Avalanche energy

UltraSO-8™ **Top View** Bottom View

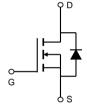


Package Type

 E_AS

 P_D

 P_{DSM}



Minimum Order Quantity

Α

mJ

W

W

AOUS66616		Ultra SO8	Tape & Reel	3000	
Absolute Maximum	n Ratings T _A =25°C	unless otherwise not	ed		
Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		V _{DS}	60	V	
Gate-Source Voltage		V_{GS}	±20	V	
Continuous Drain Current ^G	T _C =25°C	ı	92		
	T _C =100°C	I _D	80	A	
Pulsed Drain Current ^C		I _{DM}	330		
Continuous Drain Current	T _A =25°C	ı	33	٨	
	T _A =70°C	IDSM	26	A	

Junction and Storage Temperature R	Range T	J, T _{STG}	-55	°C	
Thermal Characteristics					
Parameter	s	Symbol	Тур	Units	
Maximum Junction-to-Ambient A t	≤ 10s)	15	20	°C/W
Maximum Junction-to-Ambient AD S	Steady-State	$R_{ ext{HJA}}$	40	50	°C/W
Maximum Junction-to-Case s	Steady-State R	2	1 1	1 35	°C/W



Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions			Тур	Max	Units		
STATIC PARAMETERS									
BV _{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		60			V		
I _{DSS}	Zero Gate Voltage Drain Current	V_{DS} =60V, V_{GS} =0V				1	μA		
	Zero Gate Voltage Drain Gurrent	T _J =55°C				5	μΑ		
I_{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} =±20V				±100	nA		
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$		2.4	2.9	3.4	V		
	Static Drain-Source On-Resistance	V_{GS} =10V, I_D =20A			2.6	3.3	mO		
R _{DS(ON)}		T _J =125°C			4.1	5.2	mΩ		
		V_{GS} =6V, I_D =20A			3.5	4.7	mΩ		
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =20A			100		S		
V_{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V			0.7	1	V		
Is	Maximum Body-Diode Continuous Current ^G					92	Α		
DYNAMI	CPARAMETERS								
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =30V, f=1MHz			2870		pF		
C _{oss}	Output Capacitance				940		pF		
C _{rss}	Reverse Transfer Capacitance				38		pF		
R_g	Gate resistance	f=1MHz		0.6	1.25	1.9	Ω		
SWITCH	NG PARAMETERS								
Q _g (10V)	Total Gate Charge				42.5	60	nC		
Q_{gs}	Gate Source Charge	V _{GS} =10V, V _{DS} =30V, I _D =20A			12		nC		
Q_{gd}	Gate Drain Charge				10		nC		
Q _{oss}	Output Charge	$V_{GS}=0V$, $V_{DS}=30V$			54		nC		
t _{D(on)}	Turn-On DelayTime				14.5		ns		
t _r	Turn-On Rise Time	V_{GS} =10V, V_{DS} =30V, R_{L} =1.5 Ω , R_{GEN} =3 Ω			15.5		ns		
t _{D(off)}	Turn-Off DelayTime				33		ns		
t _f	Turn-Off Fall Time				12.5		ns		
t _{rr}	Body Diode Reverse Recovery Time	I _F =20A, di/dt=500A/μs			26		ns		
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20A$, di/dt=500A/ μ	S		87		nC		

A. The value of R_{aJA} is measured with the device mounted on $1in^2$ FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The Power dissipation P_{DSM} is based on R_{aJA} t≤ 10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

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B. The power dissipation P_D is based on $T_{J(MAX)}$ =150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(MAX)}$ =150° C.

D. The $R_{\theta,JA}$ is the sum of the thermal impedance from junction to case $R_{\theta,JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

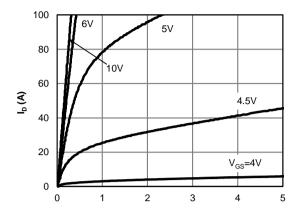
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =150° C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

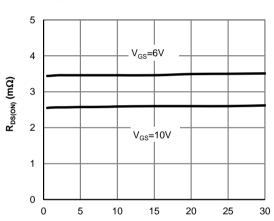
H. These tests are performed with the device mounted on 1 in FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C.



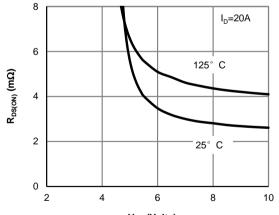
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



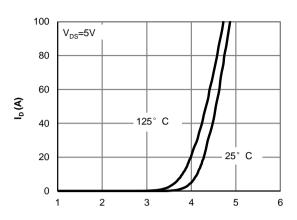
 $V_{\rm DS}$ (Volts) Figure 1: On-Region Characteristics (Note E)



 ${\rm I_D}\left({\rm A} \right)$ Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



V_{GS} (Volts) Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



V_{GS} (Volts) Figure 2: Transfer Characteristics (Note E)

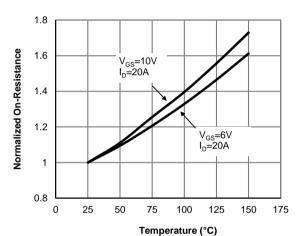
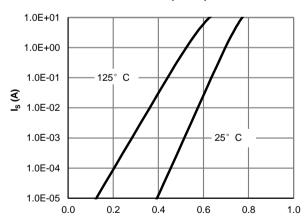


Figure 4: On-Resistance vs. Junction Temperature
(Note E)



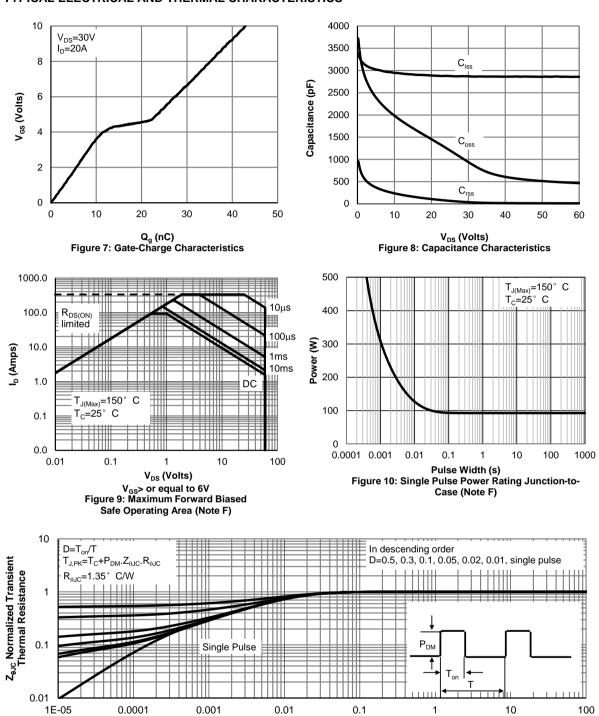
V_{SD} (Volts) Figure 6: Body-Diode Characteristics (Note E)

100

10



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

0.1

1

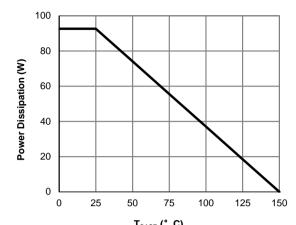
0.01

0.0001

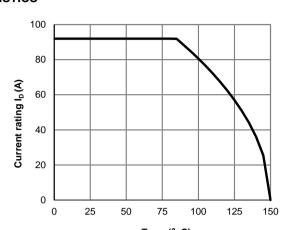
0.001



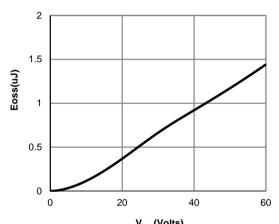
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



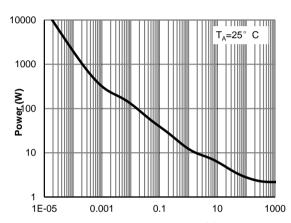
 T_{CASE} (° C) Figure 12: Power De-rating (Note F)



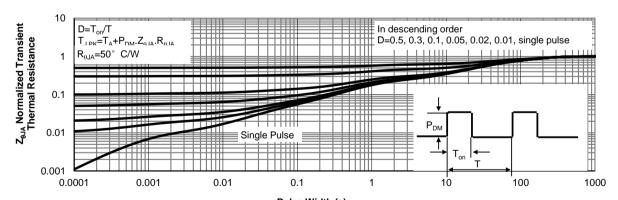
T_{CASE} (° C)
Figure 13: Current De-rating (Note F)



V_{DS} (Volts) Figure 14: Coss stored Energy



Pulse Width (s)
Figure 15: Single Pulse Power Rating Junctionto-Ambient (Note H)



Pulse Width (s)
Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

Figure A: Gate Charge Test Circuit & Waveforms

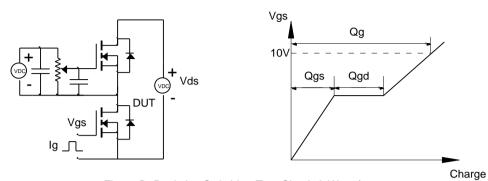


Figure B: Resistive Switching Test Circuit & Waveforms

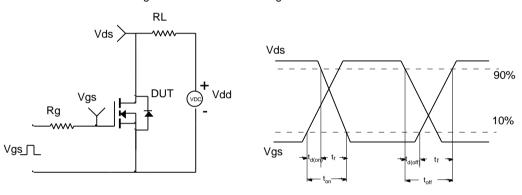


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

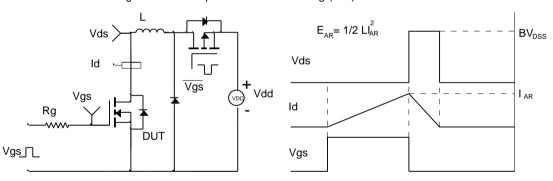


Figure D: Diode Recovery Test Circuit & Waveforms

